

SN54ABT162841, 74ABT162841 20-BIT BUS-INTERFACE D-TYPE LATCHES WITH 3-STATE OUTPUTS

SCBS665 – JUNE 1996

- Members of the Texas Instruments *Widebus*™ Family
- Output Ports Have Equivalent 25-Ω Series Resistors, so No External Resistors Are Required
- State-of-the-Art *EPIC-II B*™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce) < 0.8 V at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- High-Drive Outputs (–32-mA I_{OH} , 64-mA I_{OL})
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Package and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

SN54ABT162841 . . . WD PACKAGE
SN74ABT162841 . . . DL PACKAGE
(TOP VIEW)

1OE	1	56	1LE
1Q1	2	55	1D1
1Q2	3	54	1D2
GND	4	53	GND
1Q3	5	52	1D3
1Q4	6	51	1D4
V _{CC}	7	50	V _{CC}
1Q5	8	49	1D5
1Q6	9	48	1D6
1Q7	10	47	1D7
GND	11	46	GND
1Q8	12	45	1D8
1Q9	13	44	1D9
1Q10	14	43	1D10
2Q1	15	42	2D1
2Q2	16	41	2D2
2Q3	17	40	2D3
GND	18	39	GND
2Q4	19	38	2D4
2Q5	20	37	2D5
2Q6	21	36	2D6
V _{CC}	22	35	V _{CC}
2Q7	23	34	2D7
2Q8	24	33	2D8
GND	25	32	GND
2Q9	26	31	2D9
2Q10	27	30	2D10
2OE	28	29	2LE

description

These 20-bit latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The 'ABT162841 can be used as two 10-bit latches or one 20-bit latch. The 20 latches are transparent D-type latches. The device has noninverting data (D) inputs and provides true data at its outputs. While the latch-enable (1LE or 2LE) input is high, the Q outputs of the corresponding 10-bit latch follow the D inputs. When LE is taken low, the Q outputs are latched at the levels that were set up at the D inputs.

A buffered output-enable ($1\overline{OE}$ or $2\overline{OE}$) input can be used to place the outputs of the corresponding 10-bit latch in either a normal logic state (high or low) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly.

The outputs, which are designed to sink up to 12 mA, include 25-Ω series resistors to reduce overshoot and undershoot.



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**TEXAS
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SN54ABT162841, 74ABT162841

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description (continued)

The output-enable input does not affect the internal operation of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ABT162841 is available in TI's shrink small-outline package (DL), which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN54ABT162841 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ABT162841 is characterized for operation from -40°C to 85°C .

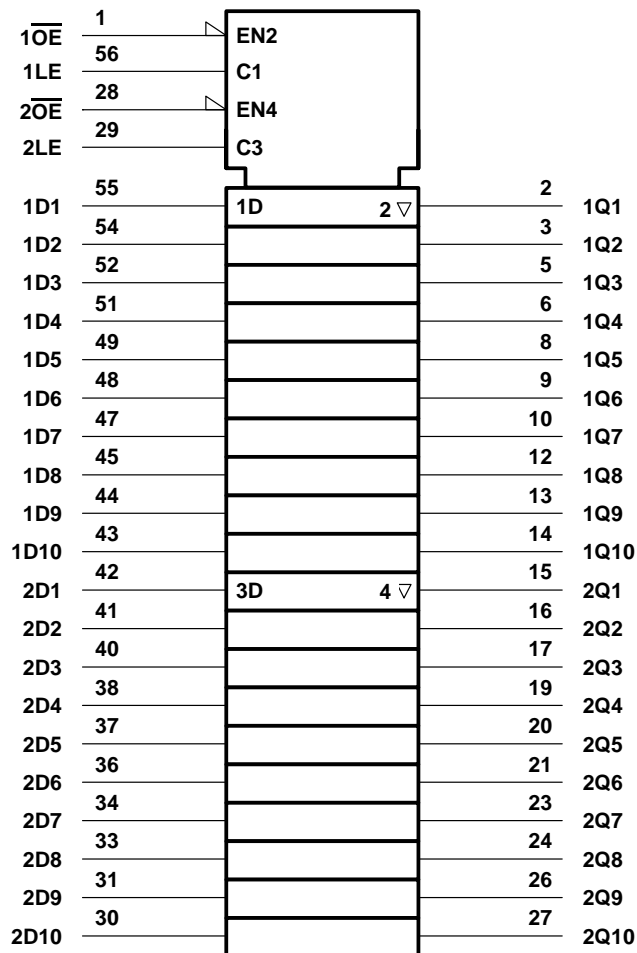
FUNCTION TABLE
(each 10-bit latch)

INPUTS			OUTPUT Q
\overline{OE}	LE	D	
L	H	H	H
L	H	L	L
L	L	X	Q_0
H	X	X	Z

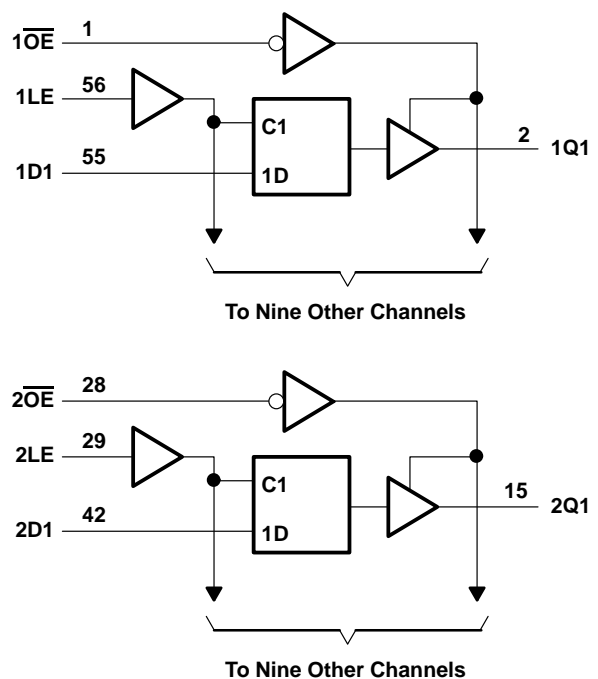
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logic symbol†



logic diagram (positive logic)



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state, V_O	–0.5 V to 5.5 V
Current into any output in the low state, I_O : SN54ABT162841	96 mA
SN74ABT162841	128 mA
Input clamp current, I_{IK} ($V_I < 0$)	–18 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Maximum power dissipation at $T_A = 55^\circ\text{C}$ (in still air) (see Note 2): DL package	1.4 W
Storage temperature range, T_{stg}	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*.



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recommended operating conditions (see Note 3)

			SN54ABT162841		SN74ABT162841		UNIT
			MIN	MAX	MIN	MAX	
V _{CC}	Supply voltage		4.5	5.5	4.5	5.5	V
V _{IH}	High-level input voltage		2		2		V
V _{IL}	Low-level input voltage			0.8		0.8	V
V _I	Input voltage		0	V _{CC}	0	V _{CC}	V
I _{OH}	High-level output current			–12		–12	mA
I _{OL}	Low-level output current			12		12	mA
Δt/Δv	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
Δt/ΔV _{CC}	Power-up ramp rate		200		200		μs/V
T _A	Operating free-air temperature		–55	125	–40	85	°C

NOTE 3: Unused or floating inputs must be held high or low.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _A = 25°C			SN54ABT162841		SN74ABT162841		UNIT	
			MIN	TYP†	MAX	MIN	MAX	MIN	MAX		
V _{IK}		V _{CC} = 4.5 V, I _I = –18 mA	–1.2			–1.2		–1.2		V	
V _{OH}		V _{CC} = 4.5 V, I _{OH} = –1 mA	2.5			2.5		2.5		V	
		V _{CC} = 5 V, I _{OH} = –1 mA	3			3		3			
		V _{CC} = 4.5 V	I _{OH} = –3 mA	2.4			2.4		2.4		
			I _{OH} = –12 mA	2*					2		
V _{OL}		V _{CC} = 4.5 V	I _{OL} = 8 mA	0.4 0.8		0.8		0.65		V	
			I _{OL} = 12 mA	0.55*				0.8			
I _I		V _{CC} = 0 to 5.5 V, V _I = V _{CC} or GND	±1			±1		±1		μA	
I _{OZPU}		V _{CC} = 0 to 2.1 V, V _O = 0.5 to 2.7 V, $\overline{OE} = X$	±50			±50		±50		μA	
I _{OZPD}		V _{CC} = 2.1 V to 0, V _O = 0.5 to 2.7 V, $\overline{OE} = X$	±50			±50		±50		μA	
I _{OZH}		V _{CC} = 2.1 V to 5.5 V, V _O = 2.7 V, $\overline{OE} \geq 2$ V	10			10		10		μA	
I _{OZL}		V _{CC} = 2.1 V to 5.5 V, V _O = 0.5 V, $\overline{OE} \geq 2$ V	–10			–10		–10		μA	
I _{off}		V _{CC} = 0, V _I or V _O ≤ 4.5 V	±100					±100		μA	
I _{CEX}	Outputs high	V _{CC} = 5.5 V, V _O = 5.5 V	50			50		50		μA	
I _{O‡}		V _{CC} = 5.5 V, V _O = 2.5 V	–25	–75	–100	–25	–100	–25	–100	mA	
I _{CC}	Outputs high	V _{CC} = 5.5 V, I _O = 0, V _I = V _{CC} or GND	0.5			0.5		0.5		mA	
	Outputs low		89			89		89			
	Outputs disabled		0.5			0.5		0.5			
ΔI _{CC} §		V _{CC} = 5.5 V, One input at 3.4 V, Other inputs at V _{CC} or GND	1.5			1.5		1.5		mA	
C _i		V _I = 2.5 V or 0.5 V	3.5							pF	
C _o		V _O = 2.5 V or 0.5 V	9							pF	

* On products compliant to MIL-STD-883, Class B, this parameter does not apply.

† All typical values are at V_{CC} = 5 V.

‡ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		$V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$		SN54ABT162841		SN74ABT162841		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
t_w	Pulse duration, LE high or low	4		4		4		ns
t_{su}	Setup time, data before LE↓	0.8		0.8		0.8		ns
t_h	Hold time, data after LE↓	1.8		1.8		1.8		ns

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50\text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$			SN54ABT162841		SN74ABT162841		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	D	Q	2.1	3.5	4.5	2.1	5.7	2.1	5.2	ns
t_{PHL}			3	4.3	5.3	3	6.2	3	6	
t_{PLH}	LE	Q	2.1	3.5	4.5	2.1	5.6	2.1	5.4	ns
t_{PHL}			2.8	4.1	5.1	2.8	6.1	2.8	5.8	
t_{PZH}	\overline{OE}	Q	2	3.6	4.7	2	5.8	2	5.7	ns
t_{PZL}			3	4.6	5.7	3	6.7	3	6.5	
t_{PHZ}	\overline{OE}	Q	2.6	4.3	5.7	2.6	6.6	2.6	6.5	ns
t_{PLZ}			2.2	3.6	5.8	2.2	8.4	2.2	7.1	

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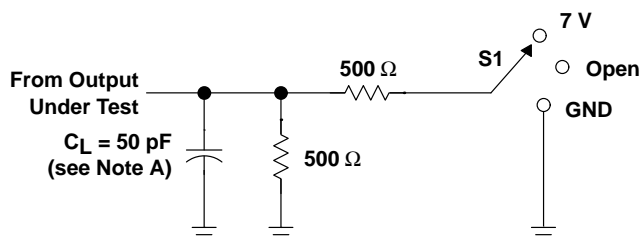


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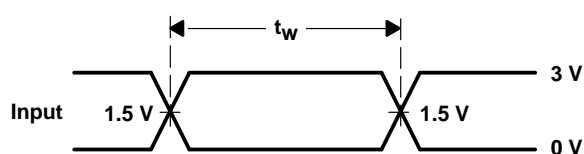
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PARAMETER MEASUREMENT INFORMATION

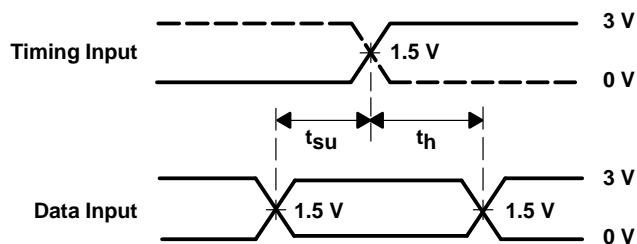


LOAD CIRCUIT

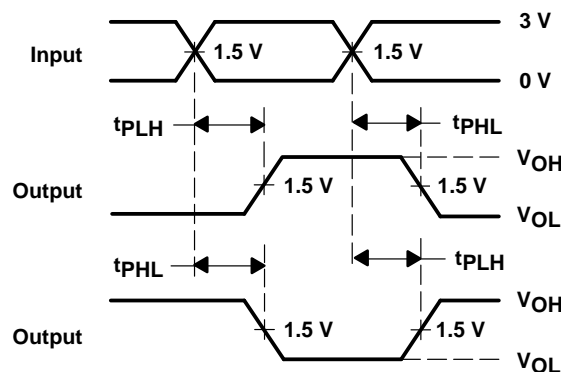
TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open



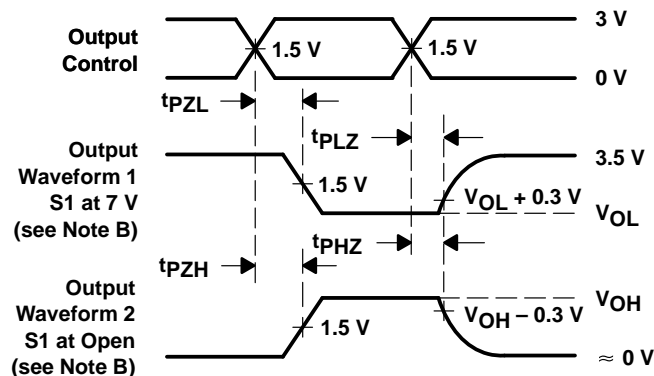
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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